

P1604ETF

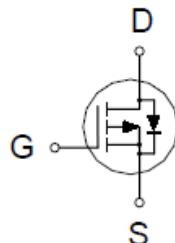
P-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-40V	16mΩ @ $V_{GS} = -10V$	-40A



TO-220F



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-40	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current $T_C = 25^\circ C$ $T_C = 100^\circ C$	I_D	-40	A
		-25	
Pulsed Drain Current ¹	I_{DM}	-120	A
Avalanche Current	I_{AS}	-40	
Avalanche Energy	E_{AS}	78	mJ
Power Dissipation $T_C = 25^\circ C$ $T_C = 100^\circ C$	P_D	42	W
		17	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3	°C / W
Junction-to-Ambient	$R_{\theta JA}$		60	

¹Pulse width limited by maximum junction temperature.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

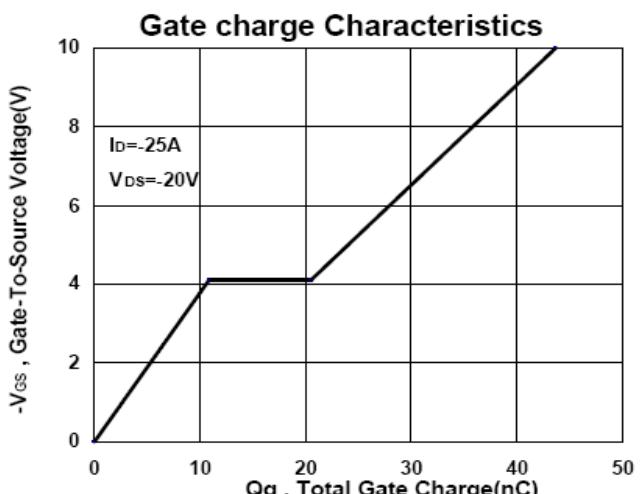
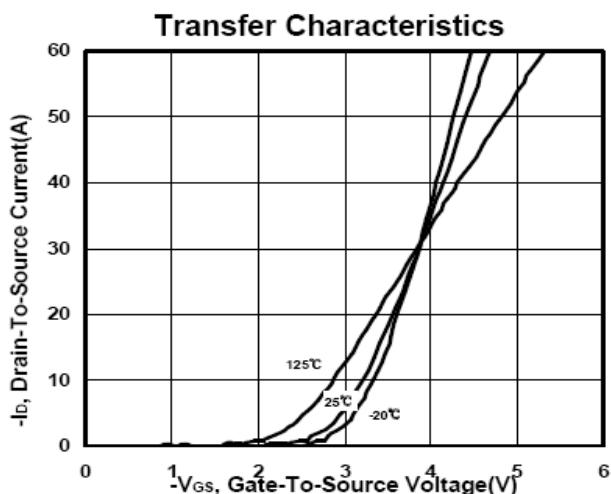
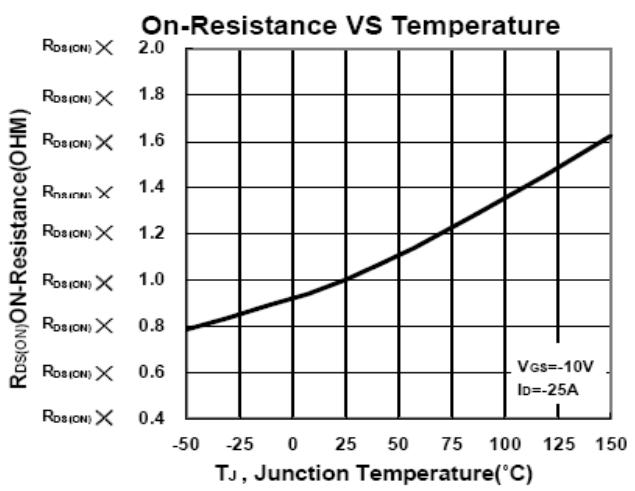
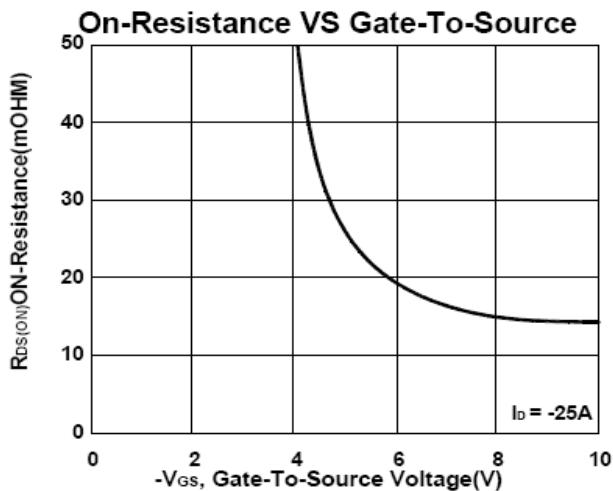
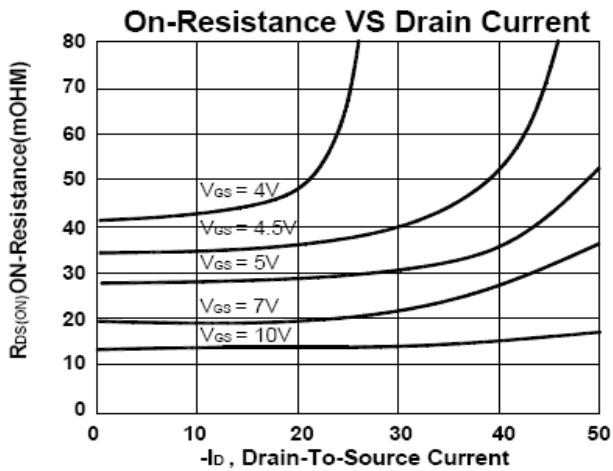
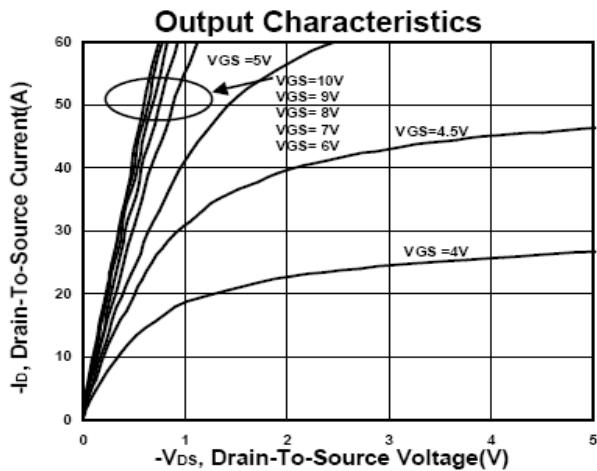
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-40			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1.5	-2.2	-3.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -32\text{V}, V_{\text{GS}} = 0\text{V}$ $V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			-1 -10	μA
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -5\text{V}, V_{\text{GS}} = -10\text{V}$	-120			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -7\text{V}, I_D = -15\text{A}$ $V_{\text{GS}} = -10\text{V}, I_D = -25\text{A}$		16 13	20 16	$\text{m}\Omega$
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -10\text{V}, I_D = -25\text{A}$		38		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -20\text{V}, f = 1\text{MHz}$		2310		pF
Output Capacitance	C_{oss}			438		
Reverse Transfer Capacitance	C_{rss}			320		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		4.3		Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, I_D = -25\text{A}, V_{\text{GS}} = -10\text{V}$		45		nC
Gate-Source Charge ²	Q_{gs}			12		
Gate-Drain Charge ²	Q_{gd}			11		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = -20\text{V}, I_D \geq -25\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GS}} = 6\Omega$		15		nS
Rise Time ²	t_r			43		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			62		
Fall Time ²	t_f			50		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-40	A
Forward Voltage ¹	V_{SD}	$I_F = -25\text{A}, V_{\text{GS}} = 0\text{V}$			-1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -25\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		43		nS
Reverse Recovery Charge	Q_{rr}			31		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

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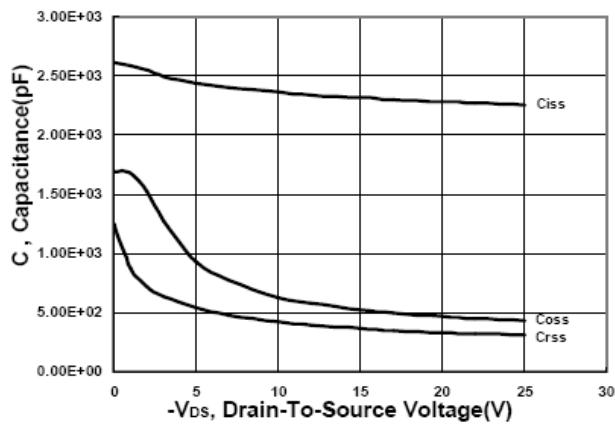
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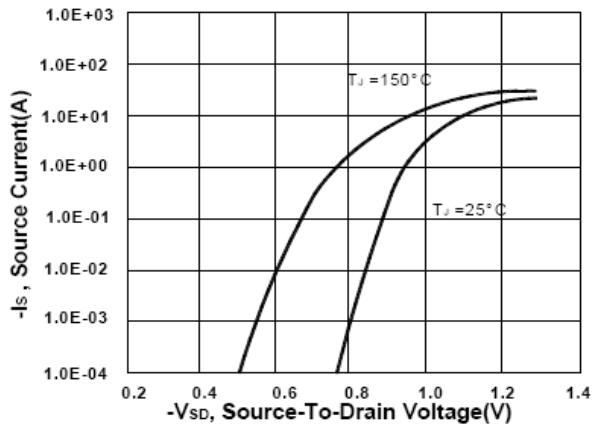
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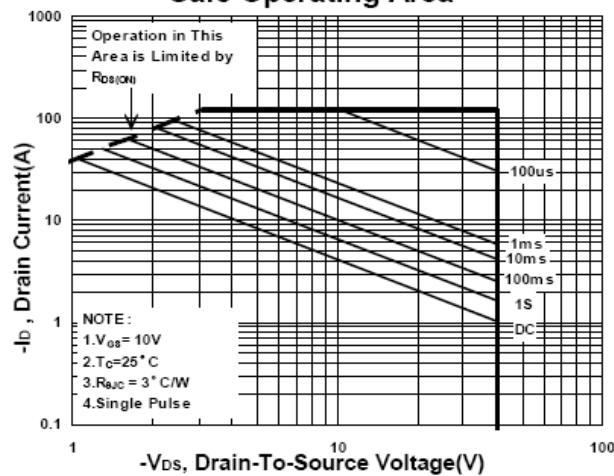
Capacitance Characteristic



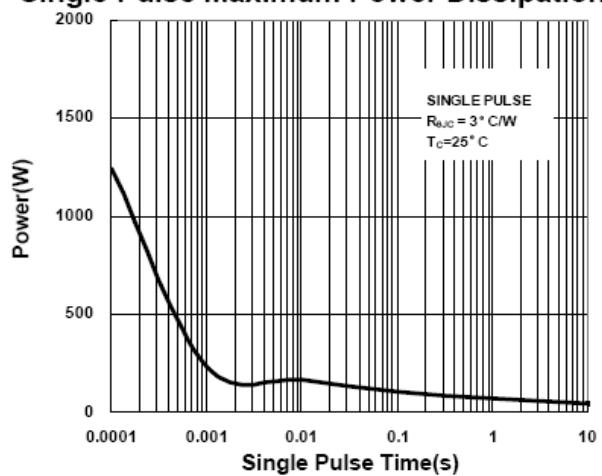
Body Diode Forward Voltage VS Source current



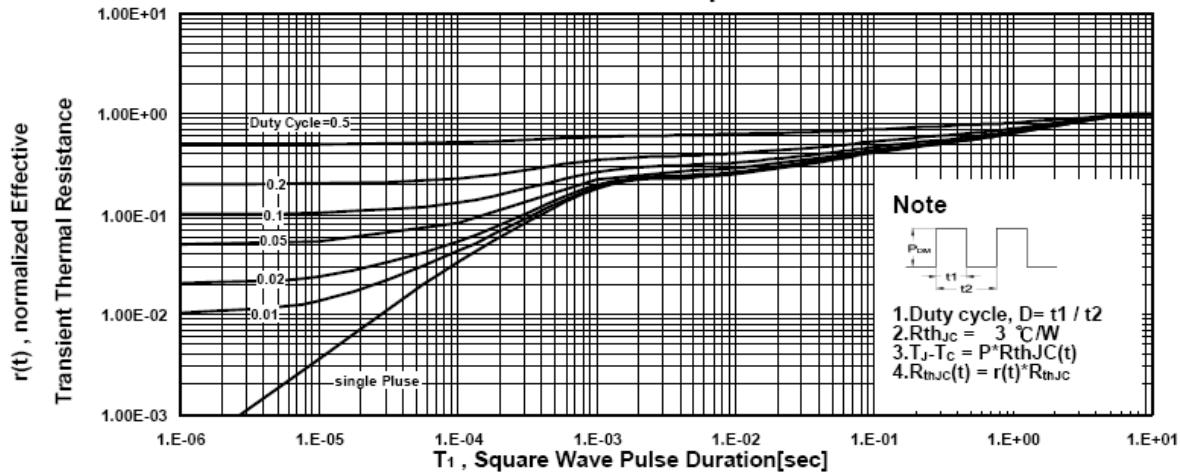
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve



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Package Dimension

TO-220F (3-Lead) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.2		4.93	e	2.05	2.55	3.05
A1	2.34		3.1	F	27.45		30.6
B	17.77		20.3	G	7.72		9.3
b	0.6		1.05	H	6.1		7.1
b1	0.9	1.23	1.62	L	12.5		14.5
b2	0.6		1.9	L1	1.97		3.8
c	0.4		1.0	P	2.98		3.4
D	14.7		16.4	Q	2.1		2.96
D1	6.4		7.5	q	3.0		3.8
E	9.7		10.4				

